

**PATENT APPLICATION**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of

Hiroki KOIKE

Appln. No.:

Group Art Unit: Unknown

Confirmation No.:

Examiner: Unknown

Filed: April 4, 2001

For: SEMICONDUCTOR MEMORY DEVICE AND TESTING SYSTEM AND TESTING METHOD

**PRELIMINARY AMENDMENT**

Commissioner for Patents  
Washington, D.C. 20231

Sir:

Prior to examination, kindly amend the above-identified application as follows:

**IN THE SPECIFICATION:**

Page 21, paragraph 4

Figures 3(a) and 3(b) show illustrations for describing problems that conventional ferroelectric memories have.

Page 22, paragraph 2

Figures 11(a) and 11(b) show circuit diagrams illustrating example arrangements of a sample hold circuit according to embodiment 2 of the invention (where the circuit is provided for one bit-line).

Hiroki KOIKE  
Q63945  
PRELIMINARY AMENDMENT

**REMARKS**

The specification has been amended to include a description of each of the figures shown in the formal drawings. Entry and consideration of this Amendment is respectfully requested.

Respectfully submitted,



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